

# SIGC223T120R2CL

IGBT Chip in NPT-technology

## FEATURES:

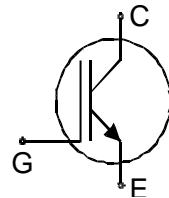
- 1200V NPT technology
- 180µm chip
- short circuit prove
- positive temperature coefficient
- easy paralleling

## This chip is used for:

- IGBT-Modules  
BSM150GB120DLC

## Applications:

- drives



Chip Type	V <sub>CE</sub>	I <sub>cn</sub>	Die Size	Package	Ordering Code
SIGC223T120R2CL	1200V	150A	14.4 x 15.5 mm <sup>2</sup>	sawn on foil	Q67041-A4687-A003

## MECHANICAL PARAMETER:

Raster size	14.4 x 15.5	mm <sup>2</sup>
Area total / active	223.2 / 189.9	
Emitter pad size	8x( 3.67x6.77 )	
Gate pad size	1.49 x 1.51	
Thickness	180	µm
Wafer size	150	mm
Flat position	90	deg
Max.possible chips per wafer	54	
Passivation frontside	Photoimide	
Emitter metalization	3200 nm Al Si 1%	
Collector metalization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding	
Die bond	electrically conductive glue or solder	
Wire bond	Al, ≤500µm	
Reject Ink Dot Size	tbd	
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month	

**MAXIMUM RATINGS:**

Parameter	Symbol	Value	Unit
Collector-emitter voltage	$V_{CE}$	1200	V
DC collector current, limited by $T_{j\max}$	$I_C$	150	A
Pulsed collector current, $t_p$ limited by $T_{j\max}$	$I_{cpuls}$	300	A
Gate emitter voltage	$V_{GE}$	$\pm 20$	V
Operating junction and storage temperature	$T_j, T_{stg}$	-55 ... +150	°C

**STATIC CHARACTERISTICS** (tested on chip),  $T_j=25$  °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V, I_C=8$ mA	1200			
Collector-emitter saturation voltage	$V_{CE(sat)}$	$V_{GE}=15V, I_C=100A$	1.5	1.8	2.25	V
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C=6mA, V_{GE}=V_{CE}$	4.5	5.5	6.5	
Zero gate voltage collector current	$I_{CES}$	$V_{CE}=1200V, V_{GE}=0V$			900	μA
Gate-emitter leakage current	$I_{GES}$	$V_{CE}=0V, V_{GE}=30V$			600	nA

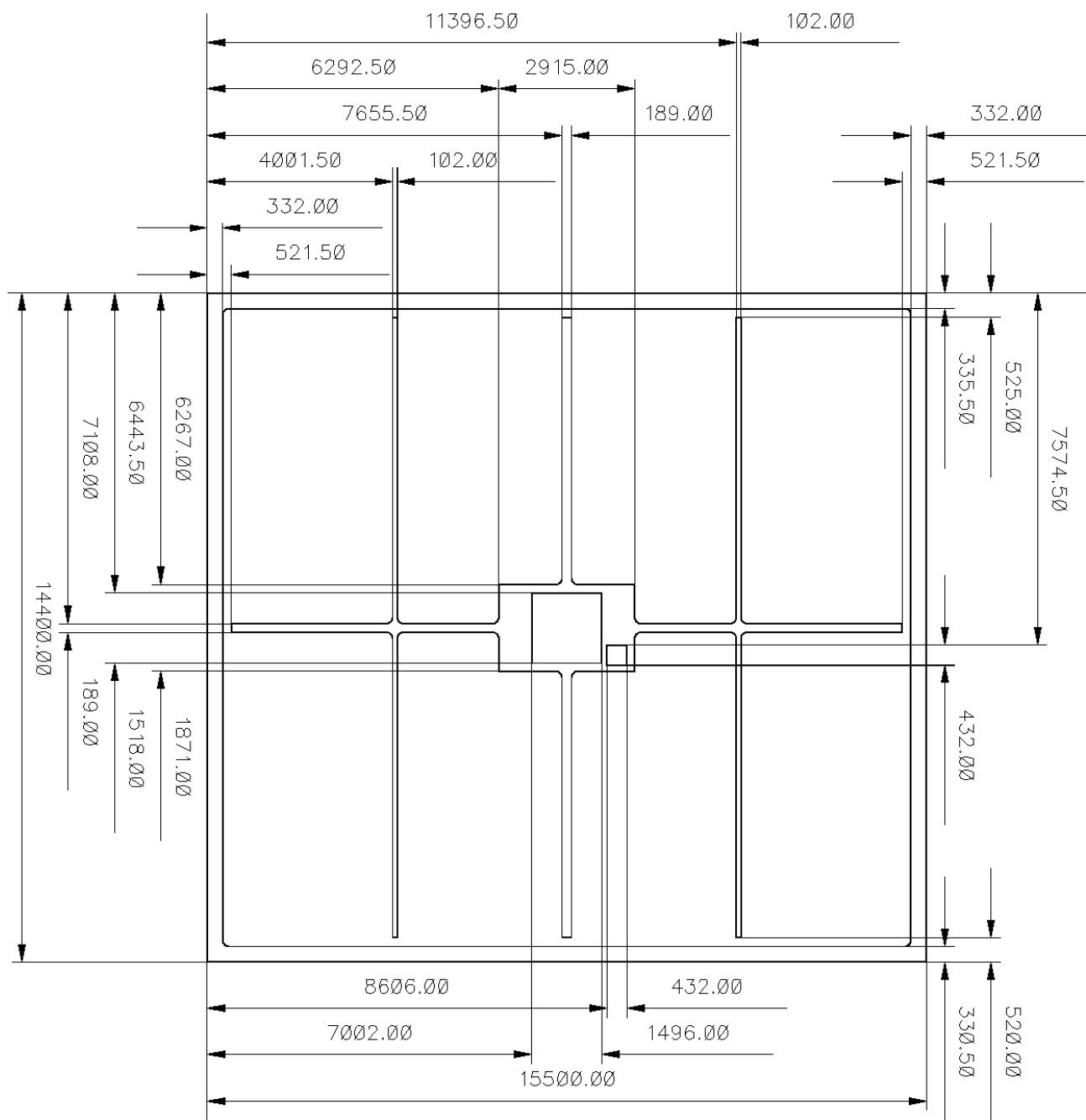
**DYNAMIC CHARACTERISTICS** (tested at component):

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Input capacitance	$C_{iss}$	$V_{CE}=25V,$	-	11	-	nF
Output capacitance	$C_{oss}$	$V_{GE}=0V,$	-	-	-	
Reverse transfer capacitance	$C_{rss}$	$f=1MHz$	-	0.7	-	

**SWITCHING CHARACTERISTICS** (tested at component), Inductive Load:

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Turn-on delay time	$t_{d(on)}$	$T_j=25$ °C	-	50	-	μs
Rise time	$t_r$	$V_{CC}=600V,$ $I_C=150A$	-	50	-	
Turn-off delay time	$t_{d(off)}$	$V_{GE}=\pm 15V,$ $R_G=5.6\Omega$	-	570	-	
Fall time	$t_f$		-	40	-	

## CHIP DRAWING:





Preliminary

# SIGC223T120R2CL

## FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the  
device data sheet

BSM150GB120DLC

Half-Bridge 62mm

### Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

**Published by**  
**Infineon Technologies AG i Gr.,**  
**Bereich Kommunikation**  
**St.-Martin-Strasse 53,**  
**D-81541 München**  
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